U.S. **UTILITY** Patent Application

APPL NUM	FILING DATE	CLASS	SUSCLASS	GAU	EXAMINER
10020208	12/18/2001	438	201	2812	AUDUONG

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Chen Henry;

2818

CONTINUING DATA VERIFIED:
THIS APPLN CLAIMS BENEFIT OF 60/312,793 08/17/2001

FOREIGN APPLICATIONS VERIFIED:

PG-PUB DO NOT PUBLISH ☐		RESCIND ☐	
Foreign priority claimed	☐ yes ☐ no		ATTORNEY DOCKET NO
35 USC 119 conditions met	☐ yes ☐ no		1875.0330001
Verified and Acknowledged Examiners's intials			

TITLE : System and method to screen defect related reliability failures in CMOS SRAMS

U.S.DEPT. OF COMM./PAT.& TM-PTO-436L(Rev. 12-94)

NOTICE OF ALLOWANCE MAILED				CLAIMS ALLOWED	
				Total Claims	Print Claim for O.G
			Assistant Examiner	DRAWING	
ISSUE FEE				Sheets Drwg.	Figs.Drwg.	Print Fig.
Amount Due	Date Paid				
			Primary Examiner		
			PREPARED FOR ISSUE	Application Examiner	
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